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NOIDA INSTITUTE OF ENGINEERING AND TECHNOLOGY, GREATER NOIDA

(An Autonomous Institute)

Affiliated to Dr. A.P.J. Abdul Kalam Technical University, Uttar Pradesh, Lucknow

M.Tech

FIRST YEAR (SEMESTER-II) THEORY EXAMINATION (2020-2021)

(Subjective Type)

Subject Code: AMTVL0211

Max. Mks. : 30

Subject: VLSI Testing and Testability

Time : 50 Minutes

General Instructions:

All questions are compulsory.

Question No. 1 to 15 are subjective type question carrying 3 marks each. Attempt any 10 out of 15 questions.

Q.No	Question Content	Question Image	Category	Sub Category	Marks	Options Randomization	Type	Difficulty
1	What do you mean by stuck at fault?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
2	What is fault collapsing?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
3	Write the differences between verification and test.		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
4	What do you mean by fan out oriented algorithm?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
5	List the various algorithms for ATPG used in combinational circuit		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
6	What is D drive in PODEM algorithm?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
7	What do you mean by boundary scan?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
8	Why Sequential ATPG are not widely used in industry?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
9	Why iterative test generation method is time consuming?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant

Q.No	Question Content	Question Image	Category	Sub Category	Marks	Options Randomization	Type	Difficulty
10	Define delay faults.		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
11	What is coupling fault?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
12	Explain the concept of IDDQ testing.		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
13	What are the difficulties in psuedo random testing?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
14	What are the differences between compression and compaction?		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant
15	Write the role of comparator in BIST architecture.		Attempt any 10 questions	10 x 3=30	3		Subjective	Brilliant